NANO 703/703L – Fall 2017 Instrumentation for Characterization of Nanomaterials Course Schedule

WEEK	DATE	TEXT	LECTURE
1	M-8/21	TEM: PART 1-BASICS	Notes: Transmission Electron Microscopy
	W-8/23	(Ch. 1-6,8,9)	Notes: Scattering & Diffraction
	F-8/25		
2	M-8/28		Notes: Elastic Scattering
	W-8/30		Notes: Inelastic Scattering
	F-9/1		Notes: Electron Sources
3	W-9/6		Notes: Lenses, Apertures, & Resolution
	F-9/8		Notes: Pumps & Holders
4	M-9/11		Notes: The Instrument
	W-9/13	TEM: PART 2-DIFFRACTION	Notes: Electron Diffraction
	F-9/15	(Ch. 11-14,16-21)	Notes: Reciprocal Space
5	M-9/18		Notes: Diffracted Beams
	W-9/20		Notes: Dynamical Diffraction
	F-9/22		
6	M-9/25		Notes: Diffraction from Crystals
	W-9/27		Notes: Diffraction from Small Volumes
	F-9/29		
7	M-10/2		Notes: Indexing Diffraction Patterns
	W-10/4		Notes: Kikuchi Diffraction
	F-10/6		Notes: Convergent Beam Diffraction
8	W-10/11		Review: Exam I
	F-10/13		Notes: Uses of CBED
9	M-10/16	TEM: PART 3-IMAGING	Notes: Amplitude Contrast
	W-10/18	(Ch. 22-26,38,30,31)	Notes: Phase Contrast
	F-10/20		Notes: Column Approximation
10	M-10/23		Notes: Planar Defects
	W-10/25		Notes: Strain Fields
	F-10/27		
11	M-10/30		Notes: High-Resolution Imaging
	W-11/1		Notes: Image Simulation
	F-11/3		C C
13	M-11/6	TEM: PART 4-SPECTROMETRY	Notes: Energy-Dispersive X-Ray Spectrometry
	W-11/8	(Ch. 32-34)	Notes: Quantitative EDX
14	M-11/13	, , , , , , , , , , , , , , , , ,	
	W-11/15		Review: Exam II
	F-11/17	XRD: Properties of X-Rays	Notes: X-Ray Diffraction
15	M-11/20	- •	Notes: Intensity Factors
16	M-11/27		Notes: Powder XRD
-	W-11/29		Notes: XRD of Epitaxial Films
	F-12/1		······································
17	M-12/4	Conclusion	Review-Final

Exam I: W-10/11, 7:00-8:50 PM, EP 251A Exam II: W-11/15, 7:00-8:50 PM, EP 251A Final: TBD

EXPERIMENT	LOCATION
TEM Magnification Calibration	EP 112
TEM Diffraction Calibration	EP 112
TEM Analysis of Nanoparticles	EP 112
TEM Analysis of Carbon Nanotubes	EP 112
TEM Sample Prep I-Ultramicrotomy	EP 211
TEM Sample Prep II-Polishing, Dimpling, Ion Milling	EP 240
tomic Force Microscopy	MI 127
Raman Spectroscopy	MI 234
Optical Spectroscopy-Absorbance and Photoluminesence	EP 211
Double-Crystal X-Ray Diffraction	EP 109
Scanning Electron Microscopy	MI 234
Ellipsometry	EP 211
Convergent Beam Electron Diffraction	EP 112
TEM Dark-Field Imaging	EP 112
Scanning TEM/Energy Dispersive X-ray Spectrometry	EP 112
Transmission Electron Tomography	EP 112
other	To Be Announced

Note: Experiment list is subject to change.